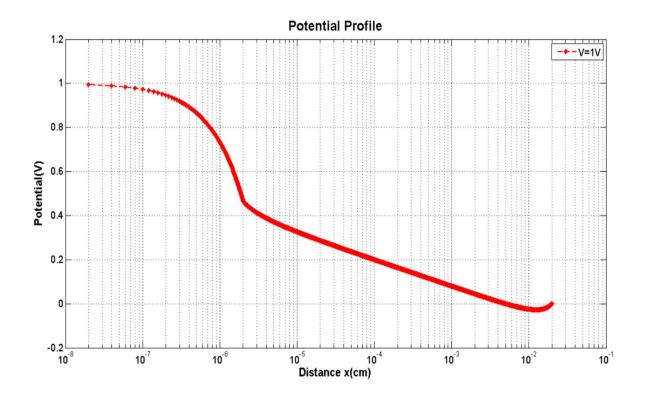
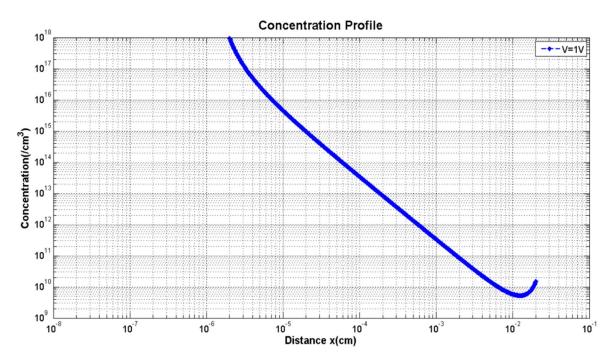
Solution of problem sheet 5

Solution f





In this solution we have consider a uniform grid points in oxide and non-uniform grid point spacing in semiconductor.

At point 'A',

Where d[i], d[i-1], d[i+1]= Position of grid points

Taylor's Series expansion of any function is

$$f(x - h_i) = f(x) - \frac{f'(x)}{1!}(h_i) + \frac{f''(x)}{2!}h_i^2 \dots so on \dots (2)$$

Neglecting higher order terms

Multiply equation (1) and (2) by and respectively and adding them, gives us

$$f''(x) = \frac{f(x+h_{i+1}) * h_i - (h_i + h_{i+1})f(x) + f(x-h_i) * h_{i+1}}{(h_{i+1}^2 * h_i + h_i^2 * h_{i+1})/2}$$

In numerical form,

$$f'' = \frac{f_{i+1} * h_i - f_i * (h_i + h_{i+1}) + f_{i-1} * h_{i+1}}{(h_{i+1}^2 * h_i + h_i^2 * h_{i+1})/2}$$

Now, the Poisson's equation from previous questions is

$$\frac{\partial^2 V_i}{\partial x^2} = \frac{q}{\epsilon} \left(n_i \exp\left(\frac{V_i}{kT}\right) \right)$$

The finite difference form would be

$$\frac{V_{i+1} * h_i - V_i * (h_i + h_{i+1}) + V_{i-1} * h_{i+1}}{(h_{i+1}^2 * h_i + h_i^2 * h_{i+1})/2} = \frac{q}{\epsilon} \left(n_i \exp\left(\frac{V_i}{kT}\right) \right)$$

$$V_{i+1} * h_i - V_i * (h_i + h_{i+1}) + V_{i-1} * h_{i+1} = \frac{q}{\epsilon} * \frac{(h_{i+1}^2 * h_i + h_i^2 * h_{i+1})}{2} * \left(n_i \exp\left(\frac{V_i}{kT}\right)\right)$$

For n cases, the system of equations would look like

$$V_1 = V_a$$

$$V_3 * h_2 - V_2 * (h_2 + h_3) + V_1 * h_3 = \frac{q}{\epsilon} * \frac{\left(h_3^2 * h_2 + h_2^2 * h_3\right)}{2} * \left(n_i \exp\left(\frac{V_2}{kT}\right)\right)$$

$$V_4 * h_3 - V_3 * (h_3 + h_4) + V_2 * h_4 = \frac{q}{\epsilon} * \frac{(h_4^2 * h_3 + h_3^2 * h_4)}{2} * (n_i \exp(\frac{V_3}{kT}))$$

$$V_n = V_b$$

Where are boundary conditions.

Because of 20nm oxide on the semiconductor the function and its jacobian is changed as

following:

$$V_{1} - V_{a}$$

$$\in_{ox} * V_{3} - 2 \in_{ox} * V_{2} + \in_{ox} * V_{1}$$

$$\in_{ox} * V_{4} - 2 \in_{ox} * V_{3} + \in_{ox} * V_{2}$$

$$\vdots$$

$$\vdots$$

$$\vdots$$

$$\vdots$$

$$\vdots$$

$$\vdots$$

$$\vdots$$

$$V_{N1-1} - 2 \in_{ox} * V_{N1-1} + \in_{ox} * V_{N1-2}$$

$$\in_{Si} * V_{N1+1} - (\in_{ox} + \in_{Si}) * V_{N1} + \in_{ox} * V_{N1-1} - \frac{dx^{2} * q * n_{i} * e^{\frac{dV_{i}}{kT}}}{\in_{o}}$$

$$V_{N1+2} * h_{N1} - V_{N1+1} * (h_{N1} + h_{N1+1}) + V_{N1} * h_{N1+1} - \frac{q}{\epsilon} * \frac{(h_{N1+1}^{2} * h_{N1} + h_{N1}^{2} * h_{N1+1})}{2} * (n_{i} \exp(\frac{V_{3}}{kT}))$$

$$\vdots$$

$$V_{i+1} * h_{i} - V_{i} * (h_{i} + h_{i+1}) + V_{i-1} * h_{i+1} - \frac{q}{\epsilon} * \frac{(h_{i+1}^{2} * h_{i} + h_{i}^{2} * h_{i+1})}{2} * (n_{i} \exp(\frac{V_{i}}{kT}))$$

$$V_{N} - V_{b}$$

So dx= distance between the two grid point in oxide region.

Here N1 grid point is boundary point of oxide layer and semiconductor.

$$\mathsf{Df} = \begin{bmatrix} 1 & 0 & 0 & 0 & \dots & 0 \\ \in \mathsf{ox} & -2^* \in \mathsf{ox} & \in \mathsf{ox} & 0 & \dots & 0 \\ 0 & \in \mathsf{ox} & -2^* \in \mathsf{ox} & \in \mathsf{ox} & \dots & 0 \\ 0 & 0 & \in \mathsf{ox} & G(N1) & \in \mathsf{si} & \dots \\ \dots & \dots & \dots & \in \mathsf{si}^* \mathsf{h}(\mathsf{N}) & G(N-1) & \in \mathsf{si}^* \mathsf{h}(\mathsf{N}-1) \\ 0 & 0 & \dots & \dots & 0 & 1 \end{bmatrix}$$

Where, G(N1) =
$$-(\in_{ox} + \in_{Si}) - \frac{dx^2 * q^2 * n_i * e^{\frac{qV_i}{KT}}}{\in_0 * kT}$$

G(N-1)=
$$-\epsilon_{Si}*(h_{N-1}+h_N) - \frac{(h_{i+1}^2*h_i+h_i^2*h_{i+1})}{2}*\frac{q^2*n_i*e^{\frac{qV_{N-1}}{kT}}}{\epsilon_0*kT}$$